

1.Description

The SOP-8 has been modified through a customized leadframe for enhanced thermal characteristics and dual-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically.

2.2Features

- Advanced Process Technology
- Ultra Low On-Resistance
- Surface Mount

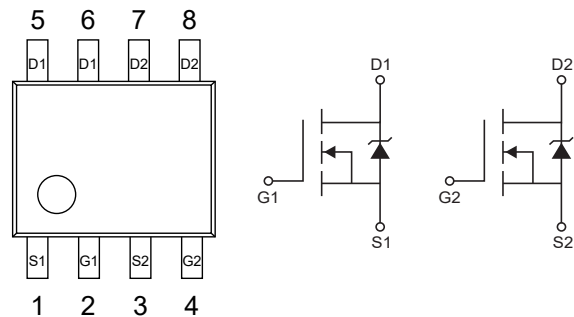
2.1Features

- $V_{DS(V)}=50V$
- $I_D=3A(V_{GS}=-10V)$
- $R_{DS(ON)}<0.13\Omega(V_{GS}=10V)$
- $R_{DS(ON)}<0.2\Omega(V_{GS}=4.5V)$

3.Pinning information

Pin	Symbol	Description
2,4	G	GATE
1,3	S	SOURCE
5,6,7,8	D	DRAIN

SOP-8



4.Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted

Parameter		Symbol	Rating	Units
Continuous Drain Current, $V_{GS}=10V$	$T_A=25^{\circ}C$	I_D	3	A
Continuous Drain Current, $V_{GS}=10V$	$T_A=100^{\circ}C$		2.3	A
Pulsed Drain Current ①		I_{DM}	10	A
Power Dissipation	$T_A=25^{\circ}C$	P_D	2	W
Linear Derating Factor			0.016	W/ $^{\circ}C$
Gate-to-Source Voltage		V_{GS}	± 20	V
Peak Diode Recovery dv/dt ②		dv/dt	4.5	V/nS
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	$^{\circ}C$



5.Thermal resistance rating

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ④	$R_{\theta JA}$		62.5	°C/W



6. Electrical Characteristics $T_J=25^{\circ}\text{C}$

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$	50			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(BR)DSS}/T_J$	$I_D=1\text{mA}$, Reference to 25°C		0.049		$\text{V}/^{\circ}\text{C}$
Static Drain-to-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10\text{V}$, $I_D=3\text{A}$ ③		0.11	0.13	Ω
		$V_{GS}=4.5\text{V}$, $I_D=1.5\text{A}$ ③		0.16	0.2	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	1		3	V
Forward Transconductance	g_{FS}	$V_{DS}=15\text{V}$, $I_D=3\text{A}$ ③		3.8		S
Drain-to-Source Leakage Current	I_{DSS}	$V_{DS}=40\text{V}$, $V_{GS}=0\text{V}$			2	μA
		$V_{DS}=40\text{V}$, $V_{GS}=0\text{V}$, $T_J=55^{\circ}\text{C}$			25	
Gate-to-Source Forward Leakage	I_{GSS}	$V_{GS}=20\text{V}$			100	nA
Gate-to-Source Reverse Leakage		$V_{GS}=-20\text{V}$			-100	
Total Gate Charge	Q_g	$I_D=2\text{A}$		12	30	nC
Gate-to-Source Charge	Q_{gs}	$V_{DS}=25\text{V}$		1.2		
Gate-to-Drain ("Miller") Charge	Q_{gd}	$V_{GS}=10\text{V}$ ③		3.5		
Turn-On Delay Time	$t_{D(on)}$	$V_{DD}=25\text{V}$		9	20	ns
Rise Time	t_r	$I_D=1\text{A}$		8	20	ns
Turn-Off Delay Time	$t_{D(off)}$	$R_G=6\Omega$		45	70	ns
Fall Time	t_f	$R_D=25\Omega$ ③		25	50	ns
Internal Drain inductance	L_D	Between lead, 6mm (0.25in.) from package and center of die contact		4		nH
Internal Source inductance	L_S			6		
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}$		290		pF
Output Capacitance	C_{oss}	$V_{DS}=25\text{V}$		140		pF
Reverse Transfer Capacitance	C_{rss}	$f=1.0\text{MHz}$		37		pF



Source-Drain Ratings and Characteristics						
Continuous Source Current (Body Diode)	I_S	MOSFET symbol showing the integral reverse p-n junction diode.			2	A
Pulsed Source Current (Body Diode) ①	I_{SM}				12	
Diode Forward Voltage	V_{SD}	$T_J=25^\circ\text{C}, I_S=1.5\text{A}, V_{GS}=0\text{V}$ ③			1.2	V
Reverse Recovery Time	t_{rr}	$T_J=25^\circ\text{C}, I_F=1.5\text{A}$		70	100	ns
Reverse Recovery Charge	Q_{rr}	$di/dt=100\text{A}/\mu\text{s}$ ③		110	170	nC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

① Repetitive rating; pulse width limited by max. junction temperature.

② $I_{SD} \leq 1.8\text{A}$, $di/dt \leq 90\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 150^\circ\text{C}$.③ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.④ Surface mounted on FR-4 board, $t \leq 10\text{sec}$.



7.1Typical Characterisitics

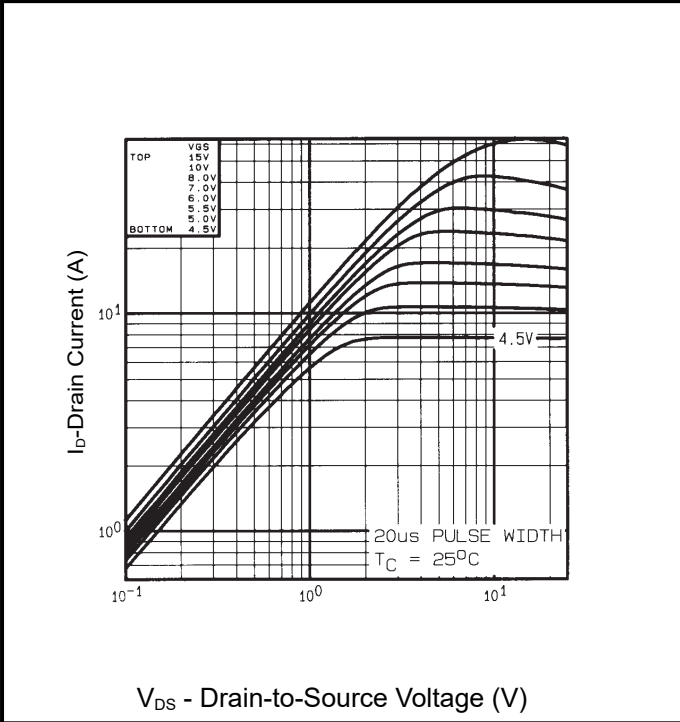


Fig 1. Typical Output Characteristics

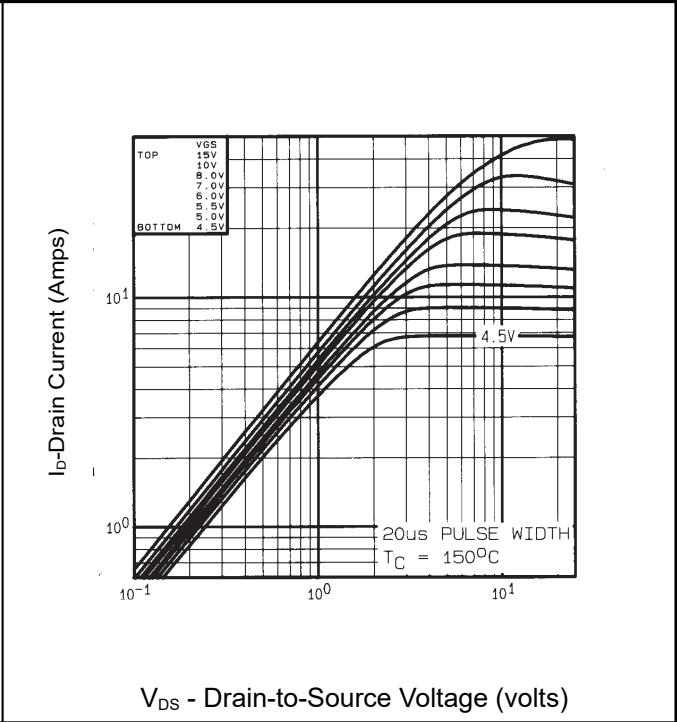


Fig 2. Typical Output Characteristics

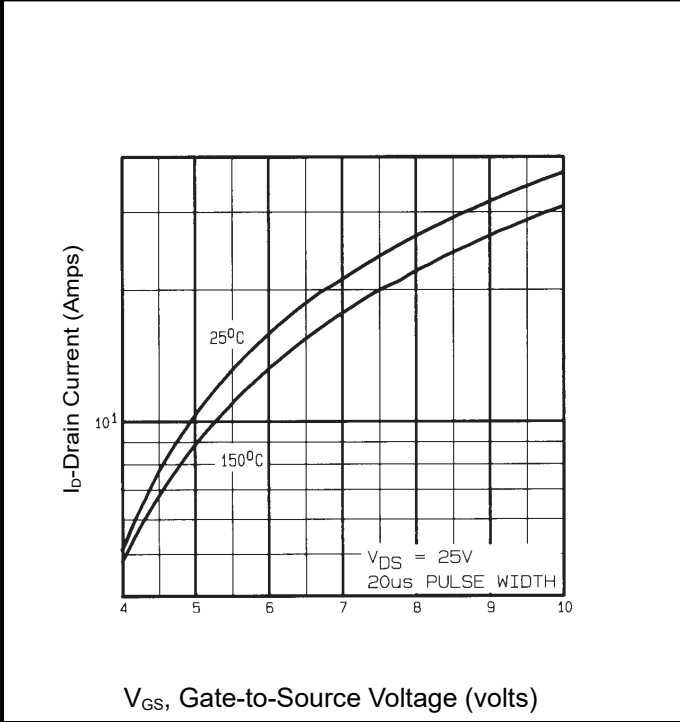


Fig 3. Typical Transfer Characteristics

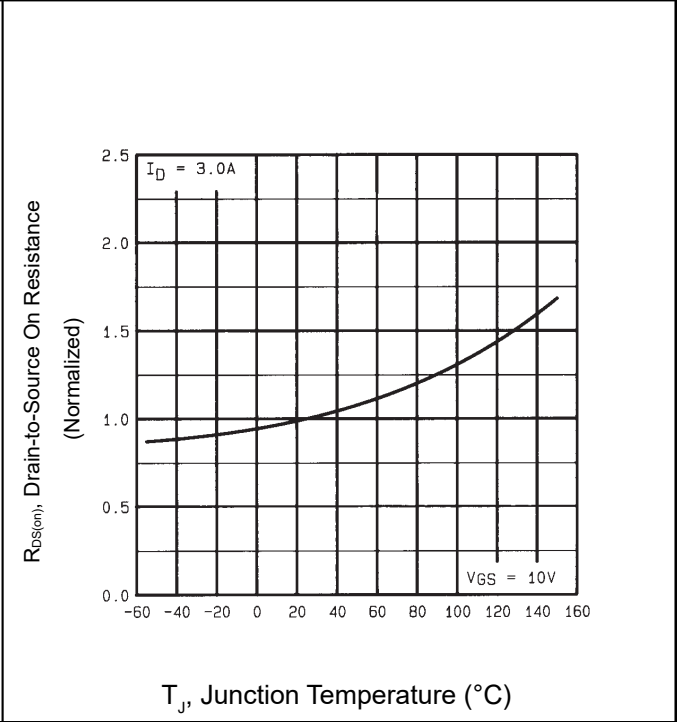
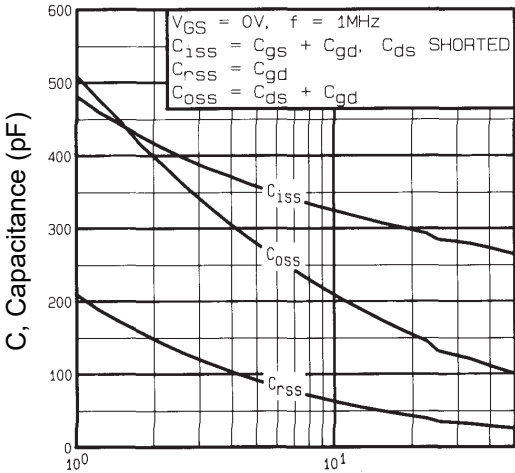
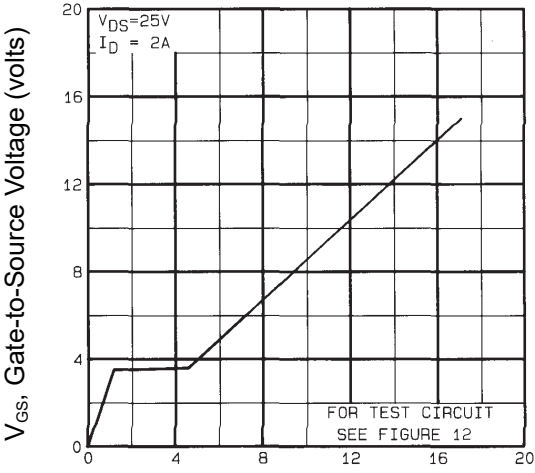
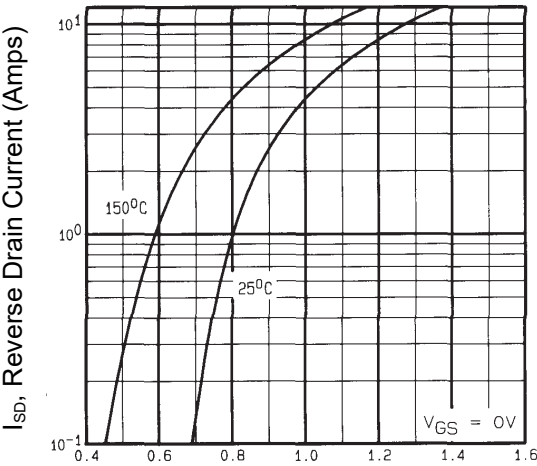
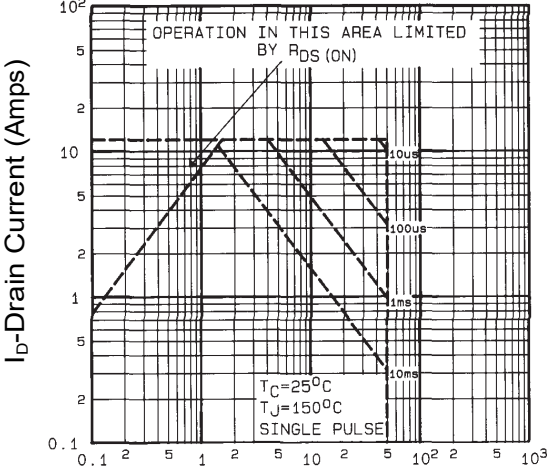


Fig 4. Nomalized On-ResistanceVs. Temperature



7.2Typical Characterisitics

 $V_{GS} = 0V, f = 1MHz$ $C_{iss} = C_{gs} + C_{gd}, C_{ds} \text{ SHORTED}$ $C_{rss} = C_{gd}$ $C_{oss} = C_{ds} + C_{gd}$ C, Capacitance (pF) V_{DS} ,Drain-to-Source Voltage (V) Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage	 $V_{DS}=25V$ $I_D = 2A$ V_{GS}, Gate-to-Source Voltage (volts) FOR TEST CIRCUIT SEE FIGURE 12 Q_G, Total Gate Charge (nC) Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage
 I_{SD}, Reverse Drain Current (Amps) $V_{GS} = 0V$ V_{SD}, Source-to-Drain Voltage (volts) Fig 7. Typical Source-Drain Diode Forward Voltage	 I_D-Drain Current (Amps) OPERATION IN THIS AREA LIMITED BY $R_{DS}(ON)$ $T_C=25^{\circ}C$ $T_J=150^{\circ}C$ SINGLE PULSE V_{DS}, Drain-to-Source Voltage (volts) Fig 8. Maximum Safe Operating Area



7.3Typical Characterisitics

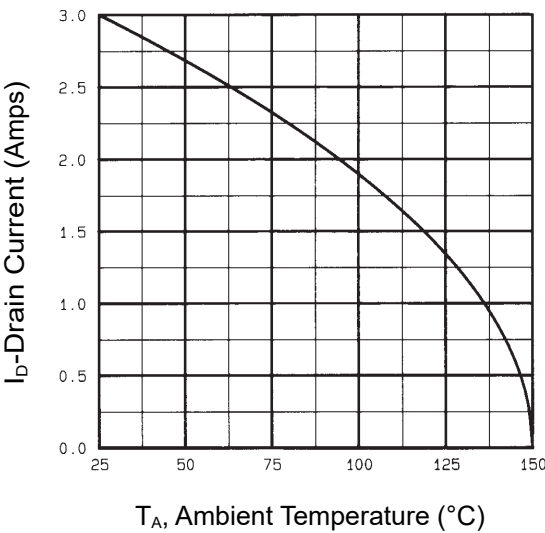


Fig 9. Maximum Drain Current Vs.AmbientTemperature

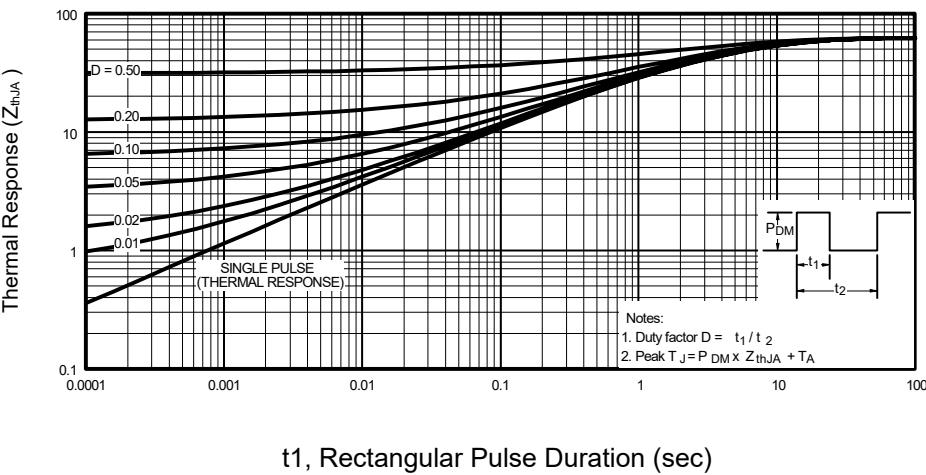


Fig 10. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient



7.4 Typical Characteristics

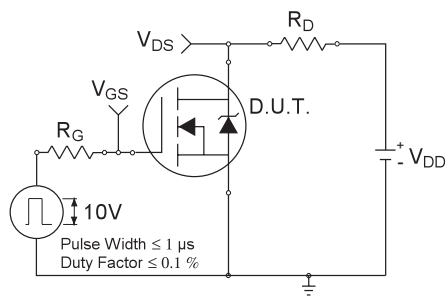


Fig 11a. Switching Time Test Circuit

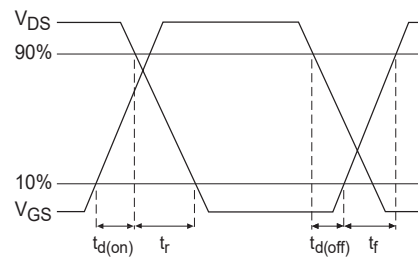


Fig 11b. Switching Time Waveforms

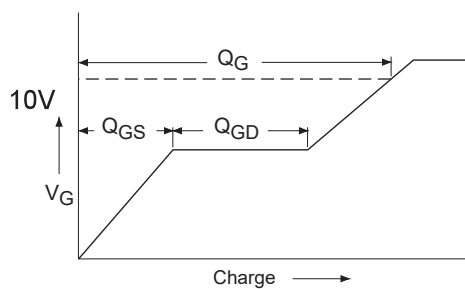


Fig 12a. Basic Gate Charge Waveform

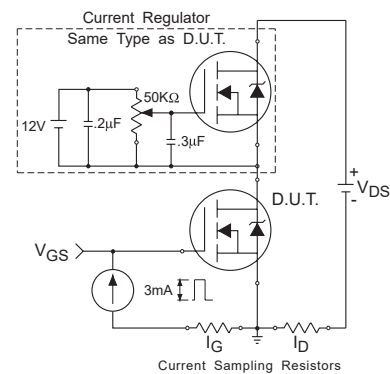
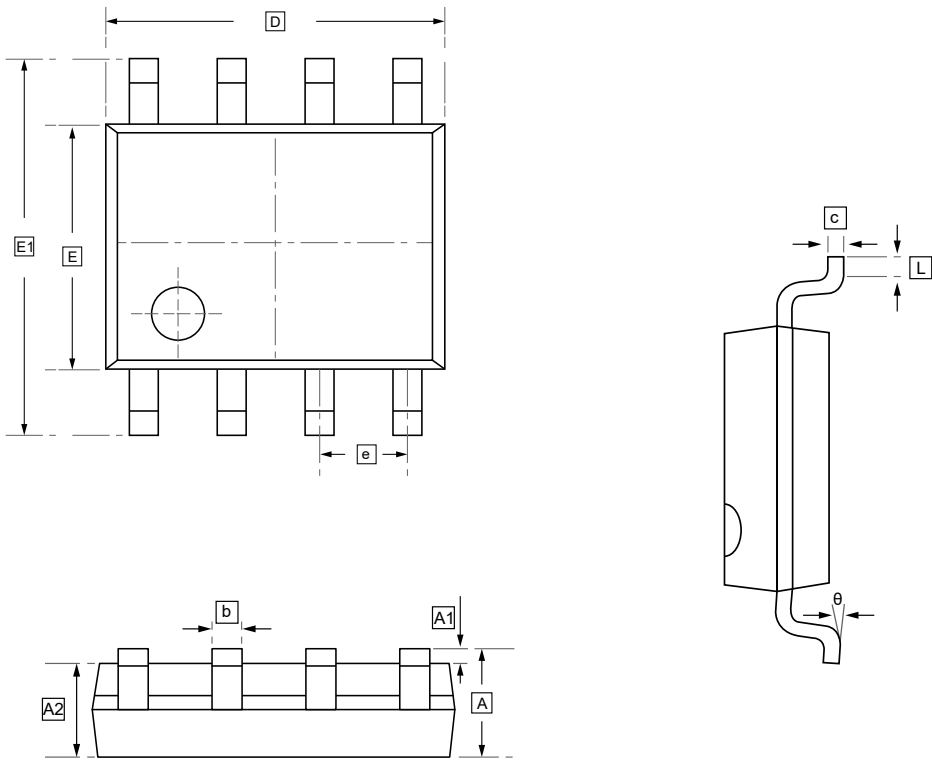


Fig 12b. Gate Charge Test Circuit



8.SOP-8 Package Outline Dimensions

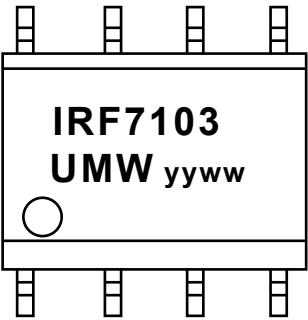


DIMENSIONS (mm are the original dimensions)

Symbol	A	A1	A2	b	c	D	E	E1	e	L	θ
Min	1.350	0.000	1.350	0.330	0.170	4.700	3.800	5.800	1.270	0.400	0°
Max	1.750	0.100	1.550	0.510	0.250	5.100	4.000	6.200	BSC	1.270	8°



9.Ordering information



yy: Year Code
ww: Week Code

Order Code	Package	Base QTY	Delivery Mode
UMW IRF7103TR	SOP-8	3000	Tape and reel



10.Disclaimer

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